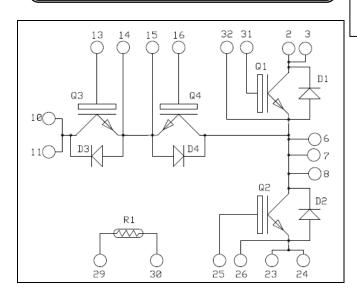
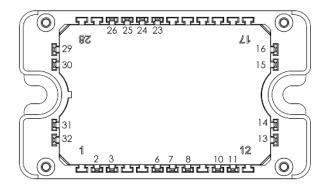


# Phase Leg & Dual Common Emitter Power Module





All multiple inputs and outputs must be shorted together 10/11 ; 23/24 ; 2/3 ;  $\ldots$ 

# APTGLQ40HR120CT3G

# High speed Trench & Field Stop IGBT4 (Q1, Q2): $V_{CES} = 1200V$ ; $I_C = 40A$ @ $Tc = 80^{\circ}C$

Trench & Field Stop IGBT3 (Q3, Q4):  $V_{CES} = 600V$ ;  $I_C = 50A$  @  $Tc = 80^{\circ}C$ 

### Application

- Solar converter
- Uninterruptible Power Supplies

#### Features

- Q1, Q2 High speed Trench + field Stop IGBT4
  - Low voltage drop
  - Low tail current
- Q3, Q4 Trench + field Stop IGBT3
  - Low voltage drop
  - Low tail current
  - Switching frequency up to 20 kHz

### • SiC Schottky Diode (D3, D4)

- Zero reverse recovery
- Zero forward recovery
- Temperature Independent switching behavior
- Positive temperature coefficient on VF
- Kelvin emitter for easy drive
- Very low stray inductance
- High level of integration
- Internal thermistor for temperature monitoring

### Benefits

- Stable temperature behavior
- Very rugged
- Solderable terminals for easy PCB mounting
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Easy paralleling due to positive T<sub>C</sub> of V<sub>CEsat</sub>
- Low profile
- RoHS Compliant

## All ratings (a) $T_j = 25^{\circ}C$ unless otherwise specified

**CAUTION:** These Devices are sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed. See application note APT0502 on www.microsemi.com



## 1. High speed Trench & Field Stop IGBT4 Phase Leg Q1&Q2 (per IGBT)

Absolute maximum ratings (per IGBT)

Symbol	Parameter	Max ratings	Unit	
V <sub>CES</sub>	Collector - Emitter Breakdown Voltage		1200	V
т	Continuous Collector Current	$T_C = 25^{\circ}C$	75	
I <sub>C</sub>	Continuous Conector Current	$T_C = 80^{\circ}C$	40	Α
I <sub>CM</sub>	Pulsed Collector Current	$T_C = 25^{\circ}C$	160	
V <sub>GE</sub>	Gate – Emitter Voltage		$\pm 20$	V
PD	Maximum Power Dissipation		250	W
RBSOA	Reverse Bias Safe Operating Area	$T_{j} = 150^{\circ}C$	80A @ 1100V	

### Electrical Characteristics (per IGBT)

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit	
I <sub>CES</sub>	Zero Gate Voltage Collector Current	$V_{GE} = 0V, V_{CE} =$			100	μA	
V	Collector Emitter Saturation Voltage	$V_{GE} = 15V$	$T_j = 25^{\circ}C$	1.7	2.05	2.4	V
V <sub>CE(sat)</sub>		$I_{\rm C} = 40 \text{A} \qquad \qquad T_{\rm j} = 150^{\circ} \text{C}$			2.6		v
V <sub>GE(th)</sub>	Gate Threshold Voltage	$V_{GE} = V_{CE}$ , $I_C = 1 \text{ mA}$		5.0	5.8	6.5	V
I <sub>GES</sub>	Gate – Emitter Leakage Current	$V_{GE} = 20V, V_{CE}$	= 0V			120	nA

## Dynamic Characteristics (per IGBT)

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
Cies	Input Capacitance	$V_{GE} = 0V$		2300		
C <sub>oes</sub>	Output Capacitance	$V_{CE} = 25V$		150		pF
Cres	Reverse Transfer Capacitance	f = 1MHz		135		
Q <sub>G</sub>	Gate charge	$V_{GE} = 15V, I_C = 40A$ $V_{CE} = 960V$		185		nC
T <sub>d(on)</sub>	Turn-on Delay Time	Inductive Switching (25°C)		30		
T <sub>r</sub>	Rise Time	$V_{GE} = \pm 15V$		57		
T <sub>d(off)</sub>	Turn-off Delay Time	$V_{Bus} = 600V$ $I_{C} = 40A$		290		ns
$T_{\rm f}$	Fall Time	$R_G = 12\Omega$		16		
T <sub>d(on)</sub>	Turn-on Delay Time	Inductive Switching (150°C)		30		
T <sub>r</sub>	Rise Time	$V_{GE} = \pm 15V$ $V_{Bus} = 600V$		49		
T <sub>d(off)</sub>	Turn-off Delay Time	$I_{\rm C} = 40$ A		366		ns
T <sub>f</sub>	Fall Time	$R_G = 12\Omega$		48		
Eon	Turn on Energy	$V_{GE} = \pm 15V \qquad T_i = 25^{\circ}C$		3.2		
Lon		$V_{Bus} = 600V$ $T_i = 150^{\circ}C$		3.75		mJ
Eoff	Turn off Energy	$I_{\rm C} = 40 \text{A}$ $T_{\rm i} = 25^{\circ} \text{C}$		1.2		
-		$R_{\rm G} = 12\Omega \qquad T_{\rm i} = 150^{\circ}{\rm C}$		2.25		
I <sub>sc</sub>	Short Circuit data	$V_{GE} \le 15V$ ; $V_{Bus} = 600V$ $t_p \le 10\mu s$ ; $T_i = 150^{\circ}C$		150		А
R <sub>thJC</sub>	Junction to Case Thermal Resistance				0.6	°C/W



### Diode ratings and characteristics (D1 & D2) (per diode)

Symbol	Characteristic	Test Conditions	1	Min	Тур	Max	Unit
V <sub>RRM</sub>	Maximum Peak Repetitive Reverse Voltage			1200			V
I <sub>RM</sub>	Maximum Reverse Leakage Current	V <sub>R</sub> =1200V				100	μΑ
I <sub>F</sub>	DC Forward Current		$Tc = 80^{\circ}C$		25		А
		$I_F = 25A$			2.6	3.1	
V <sub>F</sub>	Diode Forward Voltage	$I_F = 50A$			3.2		V
		$I_F = 25A$	$T_{j} = 125^{\circ}C$		1.8		
t	Reverse Recovery Time		$T_j = 25^{\circ}C$		320		20
t <sub>rr</sub>		$I_F = 25A$	$T_{j} = 125^{\circ}C$		360		ns
0	Reverse Recovery Charge	$V_R = 667V$ di/dt = 200A/us	$T_j = 25^{\circ}C$		480		nC
Q <sub>rr</sub>			$T_{j} = 125^{\circ}C$		1800		пС
R <sub>thJC</sub>	Junction to Case Thermal Resistance					1.4	°C/W

## 2. Trench & Field Stop IGBT3 Dual common emitter Q3&Q4 (per IGBT)

### Absolute maximum ratings (per IGBT)

Symbol	Parameter		Max ratings	Unit
V <sub>CES</sub>	Collector - Emitter Breakdown Voltage		600	V
т	Continuous Collector Current	$T_C = 25^{\circ}C$	80	
I <sub>C</sub>	Continuous Collector Current		50	Α
I <sub>CM</sub>	Pulsed Collector Current	$T_C = 25^{\circ}C$	100	
$V_{GE}$	Gate – Emitter Voltage		±20	V
PD	Maximum Power Dissipation	$T_C = 25^{\circ}C$	176	W
RBSOA	Reverse Bias Safe Operating Area	$T_{\rm J} = 150^{\circ}{\rm C}$	100A @ 550V	

## Electrical Characteristics (per IGBT)

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit	
I <sub>CES</sub>	Zero Gate Voltage Collector Current	$V_{GE} = 0V, V_{CE} =$			250	μA	
V	Collector Emitter Saturation Voltage	$V_{GE} = 15V$	$T_j = 25^{\circ}C$		1.5	1.9	V
V <sub>CE(sat)</sub>		$I_C = 50A$ $T_j =$	$T_{j} = 150^{\circ}C$		1.7		v
V <sub>GE(th)</sub>	Gate Threshold Voltage	$V_{GE} = V_{CE}, I_C = 600 \mu A$		5.0	5.8	6.5	V
I <sub>GES</sub>	Gate – Emitter Leakage Current	$V_{GE} = 20V, V_{CE}$	= 0V			600	nA



### Dynamic Characteristics (per IGBT)

·	Characteristic	Test Conditions	1	Min	Тур	Max	Unit
Cies	Input Capacitance	$V_{GE} = 0V$			3150		
C <sub>oes</sub>	Output Capacitance	$V_{CE} = 25V$			200		pF
C <sub>res</sub>	Reverse Transfer Capacitance	f = 1 MHz			95		
Q <sub>G</sub>	Gate charge	$V_{GE} = \pm 15V, I_C = V_{CE} = 300V$	= 50A		500		nC
T <sub>d(on)</sub>	Turn-on Delay Time	Inductive Switch		110			
Tr	Rise Time	$V_{GE} = \pm 15V$			45		
T <sub>d(off)</sub>	Turn-off Delay Time	$V_{Bus} = 300V$ $I_C = 50A$			200		ns
T <sub>f</sub>	Fall Time	$R_G = 8.2\Omega$		40			
T <sub>d(on)</sub>	Turn-on Delay Time	Inductive Switching (150°C)			120		
T <sub>r</sub>	Rise Time	$V_{GE} = \pm 15V$			50		
T <sub>d(off)</sub>	Turn-off Delay Time	$V_{Bus} = 300V$ $I_C = 50A$			250		ns
T <sub>f</sub>	Fall Time	$R_G = 8.2\Omega$			60		
Б	Turn-on Switching Energy	$V_{GE} = \pm 15V$	$T_j = 25^{\circ}C$		0.2		mJ
Eon	Turn-on Switching Energy	$V_{Bus} = 300V$	$T_{j} = 150^{\circ}C$		0.26		IIIJ
E <sub>off</sub>	Turn-off Switching Energy	$I_C = 50A$	$T_j = 25^{\circ}C$		1.35		mJ
Loff	Turi-on Switching Energy	$R_G = 8.2\Omega$	$T_{j} = 150^{\circ}C$		1.75		1115
I <sub>sc</sub>	Short Circuit data	$V_{GE} \le 15V$ ; $V_{Bus} = 360V$ $t_p \le 10\mu s$ ; $T_1 = 150^{\circ}C$			250		А
R <sub>thJC</sub>	Junction to Case Thermal Resistance					0.85	°C/W

## 3. SiC diode ratings and characteristics (D3 & D4) (per diode)

Symbol	Characteristic	<b>Test Conditions</b>	Min	Тур	Max	Unit	
V <sub>RRM</sub>	Maximum Peak Repetitive Reverse Voltage			600			V
T	Maximum Payarsa Laakaga Current	$V_{R} = 600V$	$T_j = 25^{\circ}C$		10	60	
I <sub>RM</sub>	Maximum Reverse Leakage Current	$\mathbf{v}_{\mathrm{R}} = 000  \mathbf{v}$	$T_{j} = 175^{\circ}C$		20	300	μA
I <sub>F</sub>	DC Forward Current		$Tc = 100^{\circ}C$		10		Α
V <sub>F</sub>	Diode Forward Voltage	$I_{\rm F} = 10A$ $T_{\rm j} = 25$	$T_i = 25^{\circ}C$		1.6	1.8	v
v <sub>F</sub>		$T_{\rm F} = 175^{\circ}{\rm C}$			2	2.4	v
Qc	Total Capacitive Charge	$I_F = 10A$ , $V_R = 6$ di/dt = 500A/µs		28		nC	
С	Total Canagitanga	$f = 1 MHz, V_R =$	200V		65		nE
C	Total Capacitance	$f = 1 MHz, V_R =$	400V		50		pF
R <sub>thJC</sub>	Junction to Case Thermal Resistance					2.5	°C/W



### 4. Thermal & package characteristics

## Temperature sensor NTC

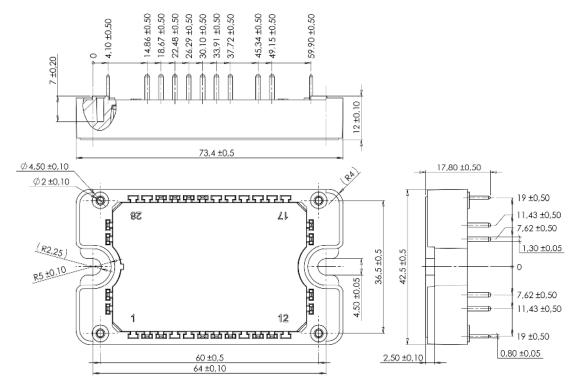
Symbol	Characteristic	Min	Тур	Max	Unit
R <sub>25</sub>	Resistance @ 25°C		22		kΩ
$\Delta R_{25}/R_{25}$	Resistance tolerance			5	%
$\Delta B/B$	Beta tolerance			3	70
B 25/100	$T_{25} = 298.16 \text{ K}$		3980		K
	D				

$$R_{T} = \frac{R_{25}}{\exp \left[ B_{25/100} \left( \frac{1}{T_{25}} - \frac{1}{T} \right) \right]}$$
 T: Thermistor temperature  
R\_{T}: Thermistor value at T

### Thermal and package characteristics

Symbol	Characteristic			Min	Тур	Max	Unit
V <sub>ISOL</sub>	RMS Isolation Voltage, any terminal to case t =1 min, 50/60Hz			4000			V
TJ	Operating junction temperature range			-40		175	
T <sub>STG</sub>	Storage Temperature Range			-40		125	°C
T <sub>C</sub>	Operating Case Temperature					100	
Torque	Mounting torque	To heatsink	M4	2		3	N.m
Wt	Package Weight					110	g

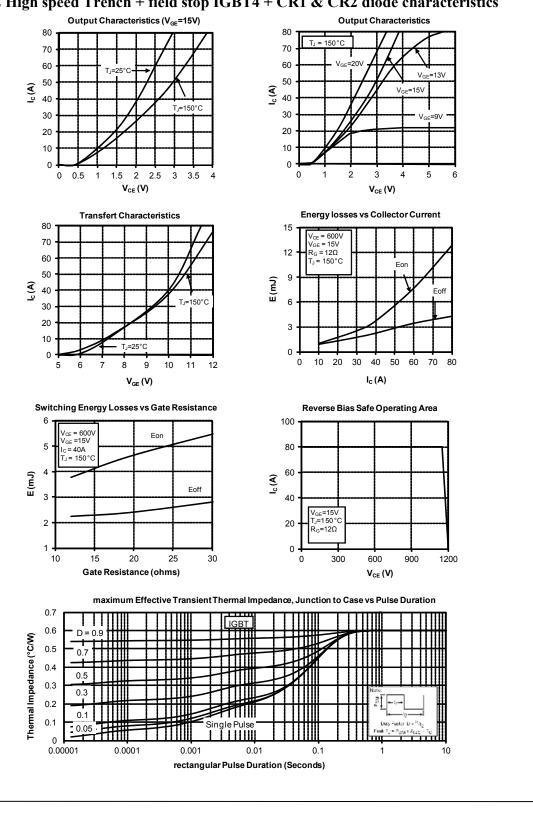
### SP3F Package outline (dimensions in mm)



#### See application note 1906 - Mounting Instructions for SP3F Power Modules on www.microsemi.com



### 5. Typical performance curve

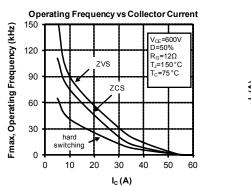


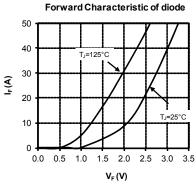
Q1, Q2 High speed Trench + field stop IGBT4 + CR1 & CR2 diode characteristics

www.microsemi.com

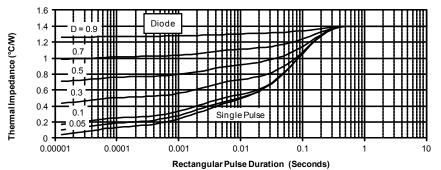
6 - 9

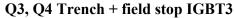


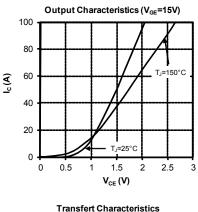


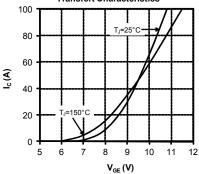


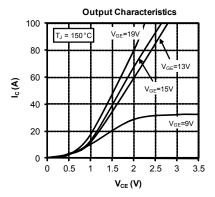
maximum Effective Transient Thermal Impedance, Junction to Case vs Pulse Duration



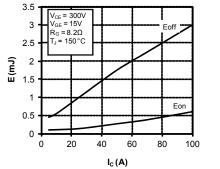


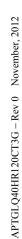




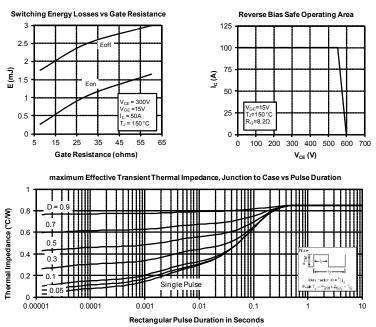




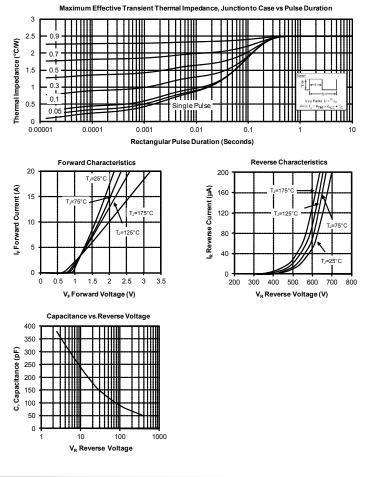








CR3 & CR4 SiC diode characteristics





#### DISCLAIMER

The information contained in the document (unless it is publicly available on the Web without access restrictions) is PROPRIETARY AND CONFIDENTIAL information of Microsemi and cannot be copied, published, uploaded, posted, transmitted, distributed or disclosed or used without the express duly signed written consent of Microsemi. If the recipient of this document has entered into a disclosure agreement with Microsemi, then the terms of such Agreement will also apply. This document and the information contained herein may not be modified, by any person other than authorized personnel of Microsemi. No license under any patent, copyright, trade secret or other intellectual property right is granted to or conferred upon you by disclosure or delivery of the information, either expressly, by implication, inducement, estoppels or otherwise. Any license under such intellectual property rights must be approved by Microsemi in writing signed by an officer of Microsemi.

Microsemi reserves the right to change the configuration, functionality and performance of its products at anytime without any notice. This product has been subject to limited testing and should not be used in conjunction with lifesupport or other mission-critical equipment or applications. Microsemi assumes no liability whatsoever, and Microsemi disclaims any express or implied warranty, relating to sale and/or use of Microsemi products including liability or warranties relating to fitness for a particular purpose, merchantability, or infringement of any patent, copyright or other intellectual property right. Any performance specifications believed to be reliable but are not verified and customer or user must conduct and complete all performance and other testing of this product as well as any user or customers final application. User or customer shall not rely on any data and performance specifications or parameters provided by Microsemi. It is the customer's and user's responsibility to independently determine suitability of any Microsemi product and to test and verify the same. The information contained herein is provided "AS IS, WHERE IS" and with all faults, and the entire risk associated with such information is entirely with the User. Microsemi specifically disclaims any liability of any kind including for consequential, incidental and punitive damages as well as lost profit. The product is subject to other terms and conditions which can be located on the web at http://www.microsemi.com/legal/tnc.asp

#### Life Support Application

Seller's Products are not designed, intended, or authorized for use as components in systems intended for space, aviation, surgical implant into the body, in other applications intended to support or sustain life, or for any other application in which the failure of the Seller's Product could create a situation where personal injury, death or property damage or loss may occur (collectively "Life Support Applications").

Buyer agrees not to use Products in any Life Support Applications and to the extent it does it shall conduct extensive testing of the Product in such applications and further agrees to indemnify and hold Seller, and its officers, employees, subsidiaries, affiliates, agents, sales representatives and distributors harmless against all claims, costs, damages and expenses, and attorneys' fees and costs arising, directly or directly, out of any claims of personal injury, death, damage or otherwise associated with the use of the goods in Life Support Applications, even if such claim includes allegations that Seller was negligent regarding the design or manufacture of the goods.

Buyer must notify Seller in writing before using Seller's Products in Life Support Applications. Seller will study with Buyer alternative solutions to meet Buyer application specification based on Sellers sales conditions applicable for the new proposed specific part.